



## Current development status and calibration plan of the X-ray CCDs onboard XRISM

#### Koji Mori (University of Miyazaki) on behalf of the XRISM/Xtend team

The 14th IACHEC meeting @ the Shonan Village Center on 2019/05/20





K. Hayashida<sup>1)</sup>, H. Tomida<sup>2)</sup>, K. Mori<sup>3)</sup>, H. Nakajima<sup>4)</sup>, T. Tanaka<sup>5)</sup>, H. Uchida<sup>5)</sup>, H. Murakami<sup>6)</sup>, T. Okajima<sup>7)</sup>, T.G. Tsuru<sup>5)</sup>, T. Kohmura<sup>8)</sup>, K. Hagino<sup>8)</sup>, S. Kobayashi<sup>8)</sup>, M. Ishida<sup>2)</sup>, Y. Maeda<sup>2)</sup>, H. Uchiyama<sup>9)</sup>, K. Yamaoka<sup>10)</sup> H.Noda<sup>1)</sup>, H. Matsumoto<sup>1)</sup>, M. Nobukawa<sup>11)</sup>, K. K. Nobukawa<sup>12)</sup>, J. S. Hiraga<sup>13)</sup>, M. Yamauchi<sup>3)</sup>, I. Hatsukade<sup>3)</sup>, H. Tsunemi<sup>1)</sup>, M. Ozaki<sup>2)</sup>, T. Dotani<sup>2)</sup>, T. Yoneyama<sup>1)</sup>, J. Iwagaki<sup>1)</sup>, K. Okazaki<sup>1)</sup>, K. Asakura<sup>1)</sup>, Y. Kanemaru<sup>3)</sup>, J. Sato<sup>3)</sup>, T. Takaki<sup>3)</sup>, Y. Nishioka<sup>3)</sup>, H. Kashimura<sup>4)</sup>, H. Okon<sup>5)</sup>, Y. Amano<sup>5)</sup>, M. Saito<sup>12)</sup>, M. Yoshida<sup>13)</sup> and the XRISM Xtend Team

#### Xtend = X-ray Mirror Assembly (XMA) + Soft X-ray Imager (SXI)

1:Osaka Univ., 2:ISAS/JAXA, 3: Univ. of Miyazaki, 4: Kanto Gakuin Univ., 5:Kyoto Univ., 6: Tohoku Gakuin Univ., 7: NASA/GSFC, 8: Tokyo Univ. of Science, 9: Shizuoka Univ., 10: Nagoya Univ., 11: Nara Univ. of Education, 12: Nara Women's Univ., 13: Kwansei Gakuin Univ.,



## **Role in XRISM**





- 2x2 mosaic with 4 chips
  - 38'×38' wide-FOV
  - complement of the narrow SXS FOV
- Effectively higher spatial resolution in spite of the same-type mirror used
  - 30" (S) vs 1.74" (I) in pix size



## M from A-H/SXI to XRISM/SXI





- Basically the same characteristics as the one used in the previous ASTRO-H satellite (Hitomi)
  - 2x2 mosaic with 4 P-ch BI CCD with a 200 µm thickness
- Two improvements
  - a notch structure of potential for signal charges by increasing the implant concentration in the channel
  - optical blocking power



### Improvement in radiation tolerance





 We performed proton radiation experiments on our new CCDs, and confirmed that introduction of a notch structure improves radiation tolerance

### XRISM Improvement in optical blocking power





- Doubling optical blocking layer significantly reduces the number of pinholes (6%→0.1%)
- Light leak from the side edge is also reduced



### **CCD screening strategy**







Schedule





- Two CCDs are delivered to us almost every two weeks
- Two deliveries were made so that we have four CCDs in our lab
- ➢ We performed the first screening experiment on April 18<sup>th</sup>
- The two CCD first delivered were examined

### **Whole Screening System**





- The screening system is built at a clean booth in a labo. of Osaka Univ.
- The CCDs are kept at -110°C and ~10<sup>-6</sup> Torr, and operated by electronics and PCs. Temperature, pressure, voltage, and current are all always monitored.
- > ON/OFF of the X-ray generator and LEDs can be controlled from outside.



### **X-ray Generator**





## **XRISM 1<sup>st</sup> screening experiment**



Two CCD chips, FM02-01 and FM02-02, were simultaneously examined
 Date were taken from the two readout so that two segments in one CCD
 Soft X-ray responses were measured with Si-Kα (1.7 keV) and O-Kα (0.52 keV) from the SiO<sub>2</sub> target and F-Kα (0.68 keV) from the the LiF target



# <sup>55</sup>Fe: CTI (1)





- Charge injection is not applied for CTI evaluation and G0 only
- Each figure shows "pulse height vs Y (number of transfer)"
- Blue dots indicate Mn-Kα data (Mn-Kβ data are excluded)
- Orange points with bar indicate average and standard deviation of the pulse heights at the Y value
- Red line indicate the best fit of the orange points
- The slope shows a charge transfer inefficiency (CTI)



55Fe: CTI (2)





- The CTI values (red) are ~2.4x10<sup>-5</sup> and ~1.6x10<sup>-5</sup> for FM02-01 and FM02-02, respectively.
- > The CTI values was also measured in the 1/8 region along the X direction (blue)
- One of the 1/8 regions in segment AB of FM02-01 shows an extraordinary high value (region 6 in the left half of the left figure)



## **55Fe: hotspot**





A hotspot, localized region with high a CTI value, was observed in Segment AB of FM02-01

# **KRISM 55Fe: Energy resolution**

Charge injection is applied and data taken in the low Y region are analyzed in order to know the



best performance

- Grade0 only
- The energy resolution is 160~175 eV (FWHM at 5.9 keV), which is comparable with the ASTRO-H SXI performance



FM02-02 CD





#### FM02-02 AB





103

102

101

100

5.0

2.5

0.0

-2.5

-5.0

100

Counts

(data - model) / error

## SiO<sub>2</sub>: dead layer (1)

FM02-01 AB center(eV): 1740.0+/-0.5
primary FWHM(eV): 161.3+/-1.1
gain(eV/ch): 5.5753

400

300

Channal

500



200



300

Channel

200

400

500

0.0



## SiO2: dead layer (2)







- The flux ratio of the O and Si lines from our system were measured with a silicon drift detector (SDD) with known quantum efficiency (Up right)
- The flux ratios of O/Si measured with the CCDs (G02346) are consistent with no dead layer case although uncertainty is still large (Bottom left)
- At least, no thick (>100 nm) dead layer exists

# Rism LiF: another example





















>Xtend/SXI is the X-ray CCD camera for XRISM, basically the same characteristic with A-H/SXI but some improvements included ➤We set up the X-ray screening/calibration system in our lab, and selecting four flight CCDs First two CCDs are as good as ASTRO-H/SXI flight CCDs